

# MOS FIELD EFFECT TRANSISTOR

## NP86N04CHE, NP86N04DHE, NP86N04EHE

### SWITCHING

### N-CHANNEL POWER MOS FET

### INDUSTRIAL USE

#### DESCRIPTION

These products are N-channel MOS Field Effect Transistor designed for high current switching applications.

#### FEATURES

- Channel temperature 175 degree rated
- Super low on-state resistance
- ★  $R_{DS(on)} = 4.4 \text{ m}\Omega \text{ MAX.}$  ( $V_{GS} = 10 \text{ V}$ ,  $I_D = 43 \text{ A}$ )
- ★ • Low  $C_{iss}$  :  $C_{iss} = 5900 \text{ pF TYP.}$
- Built-in gate protection diode

#### ABSOLUTE MAXIMUM RATINGS ( $T_A = 25^\circ\text{C}$ )

Drain to Source Voltage	$V_{DS}$	40	V
Gate to Source Voltage	$V_{GS}$	$\pm 20$	V
Drain Current (DC) <sup>Note1</sup>	$I_{D(DC)}$	$\pm 86$	A
Drain Current (Pulse) <sup>Note2</sup>	$I_{D(pulse)}$	$\pm 344$	A
Total Power Dissipation ( $T_A = 25^\circ\text{C}$ )	$P_T$	1.8	W
★ Total Power Dissipation ( $T_c = 25^\circ\text{C}$ )	$P_T$	230	W
★ Single Avalanche Current <sup>Note3</sup>	$I_{AS}$	86 / 67 / 24	A
★ Single Avalanche Energy <sup>Note3</sup>	$E_{AS}$	74 / 450 / 580	mJ
Channel Temperature	$T_{ch}$	175	$^\circ\text{C}$
Storage Temperature	$T_{stg}$	-55 to +175	$^\circ\text{C}$

- Notes**
1. Package Limit =  $\pm 75 \text{ A}$
  2.  $PW \leq 10 \mu\text{s}$ , Duty cycle  $\leq 1 \%$
  3. Starting  $T_{ch} = 25^\circ\text{C}$ ,  $R_G = 25 \Omega$ ,  $V_{GS} = 20 \text{ V} \rightarrow 0 \text{ V}$

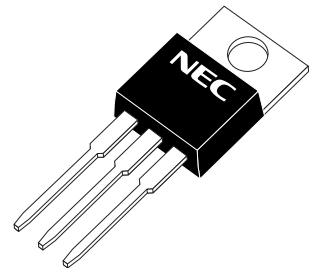
#### THERMAL RESISTANCE

★ Channel to Case	$R_{th(ch-C)}$	0.65	$^\circ\text{C/W}$
Channel to Ambient	$R_{th(ch-A)}$	83.3	$^\circ\text{C/W}$

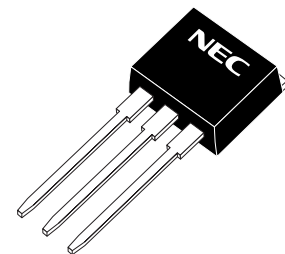
#### ORDERING INFORMATION

PART NUMBER	PACKAGE
NP86N04CHE	TO-220AB
NP86N04DHE	TO-262
NP86N04EHE	TO-263

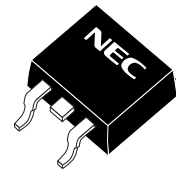
(TO-220AB)



(TO-262)



(TO-263)

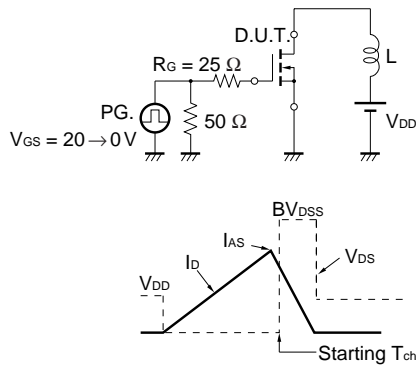


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Not all devices/types available in every country. Please check with local NEC representative for availability and additional information.

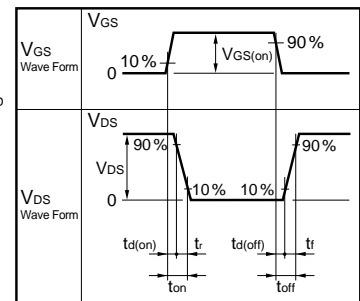
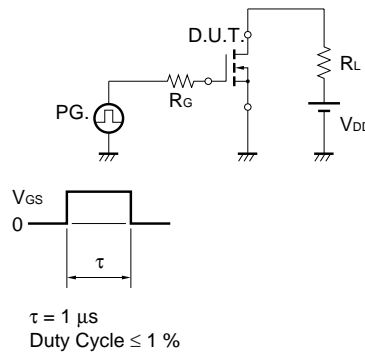
★ ELECTRICAL CHARACTERISTICS (T<sub>A</sub> = 25 °C)

CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Drain to Source On-state Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 43 A		3.5	4.4	mΩ
Gate to Source Cut-off Voltage	V <sub>GS(off)</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 250 μA	2.0	3.0	4.0	V
Forward Transfer Admittance	y <sub>fs</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 43 A	29	57		S
Drain Leakage Current	I <sub>DSS</sub>	V <sub>DS</sub> = 40 V, V <sub>GS</sub> = 0 V			10	μA
Gate to Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> = ±20 V, V <sub>DS</sub> = 0 V			±10	μA
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V, f = 1 MHz		5900	8900	pF
Output Capacitance	C <sub>oss</sub>			1200	1800	pF
Reverse Transfer Capacitance	C <sub>rss</sub>			530	960	pF
Turn-on Delay Time	t <sub>d(on)</sub>	I <sub>D</sub> = 43 A, V <sub>GS(on)</sub> = 10 V, V <sub>DD</sub> = 20 V, R <sub>G</sub> = 1 Ω		32	71	ns
Rise Time	t <sub>r</sub>			24	59	ns
Turn-off Delay Time	t <sub>d(off)</sub>			110	220	ns
Fall Time	t <sub>f</sub>			33	82	ns
Total Gate Charge	Q <sub>G</sub>	I <sub>D</sub> = 86 A, V <sub>DD</sub> = 32 V, V <sub>GS</sub> = 10 V		110	170	nC
Gate to Source Charge	Q <sub>GS</sub>			22		nC
Gate to Drain Charge	Q <sub>GD</sub>			36		nC
Body Diode Forward Voltage	V <sub>F(S-D)</sub>	I <sub>F</sub> = 86 A, V <sub>GS</sub> = 0 V		0.93		V
Reverse Recovery Time	t <sub>rr</sub>	I <sub>F</sub> = 86 A, V <sub>GS</sub> = 0 V, di/dt = 100 A/μs		70		ns
Reverse Recovery Charge	Q <sub>rr</sub>			125		nC

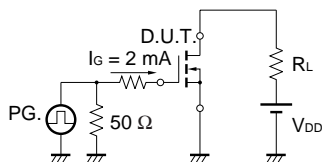
TEST CIRCUIT 1 AVALANCHE CAPABILITY



TEST CIRCUIT 2 SWITCHING TIME

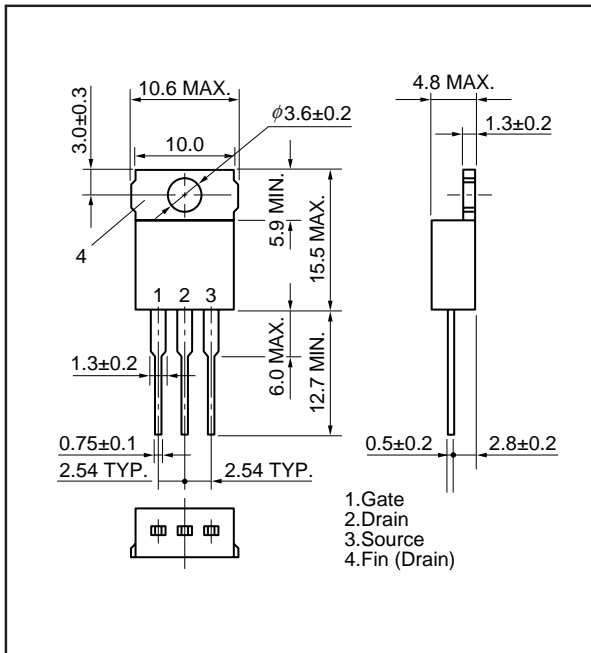


TEST CIRCUIT 3 GATE CHARGE

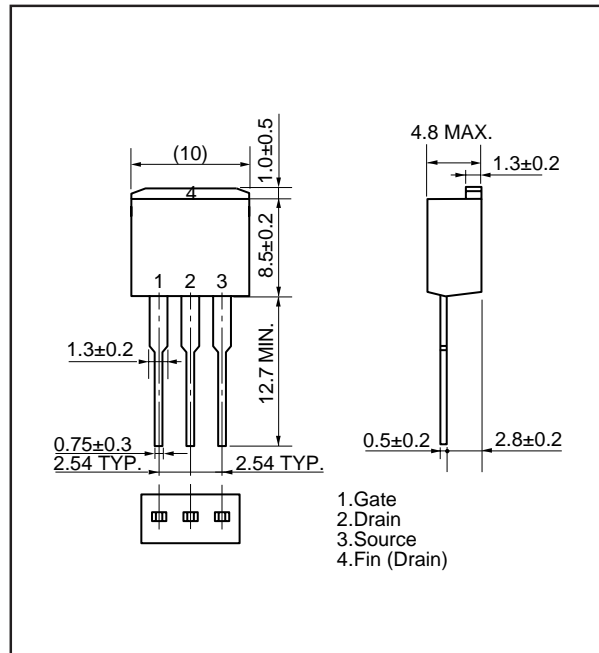


PACKAGE DRAWINGS (Unit: mm)

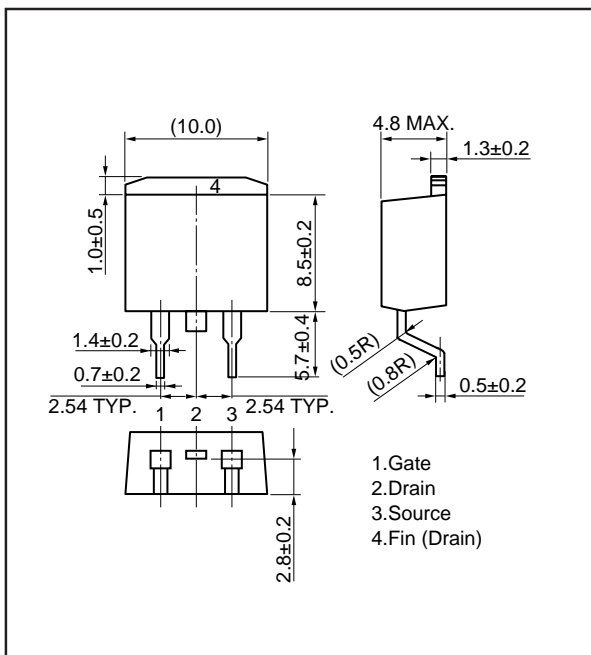
1) TO-220AB (MP-25)



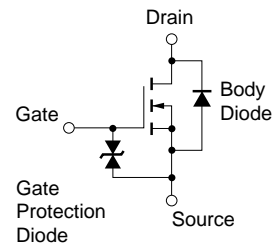
2) TO-262 (MP-25 Fin Cut)



3) TO-263 (MP-25ZJ)



EQUIVALENT CIRCUIT



**Remark** The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

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